

FIG. 1

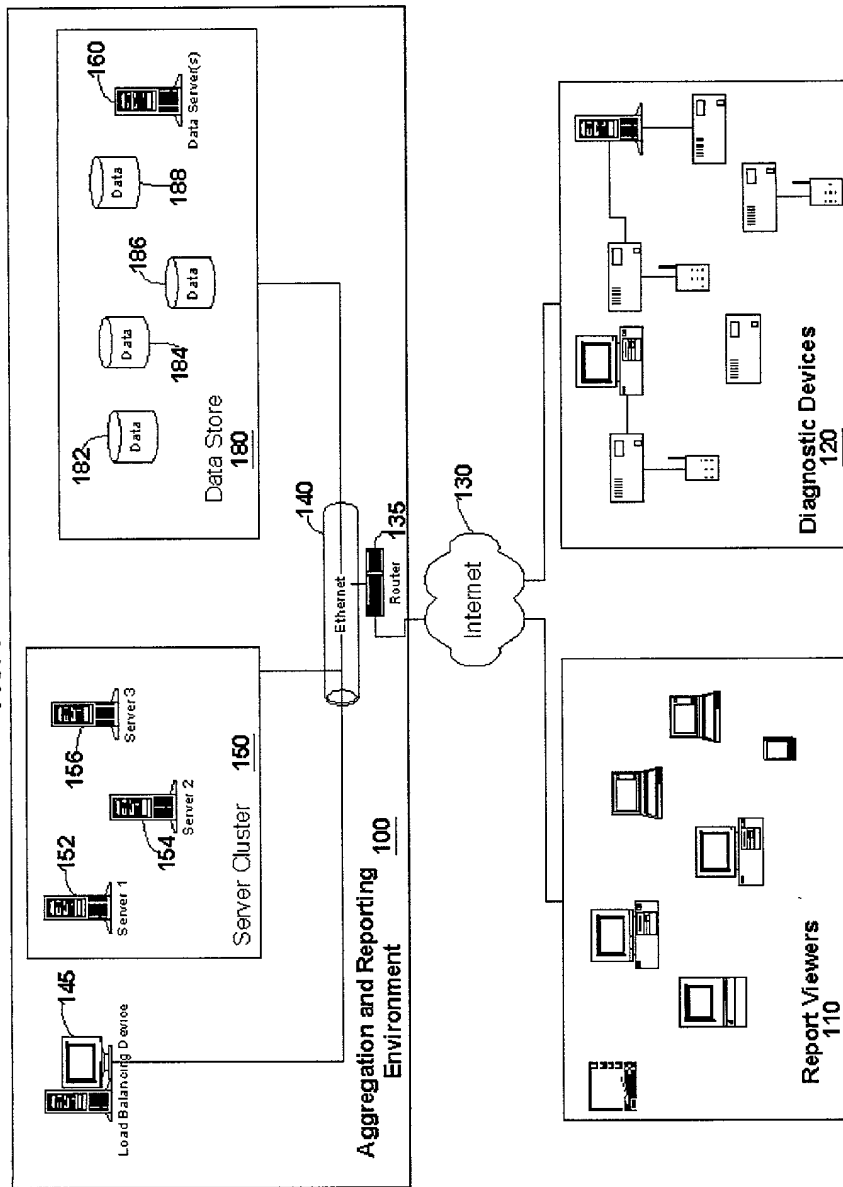


FIG. 2

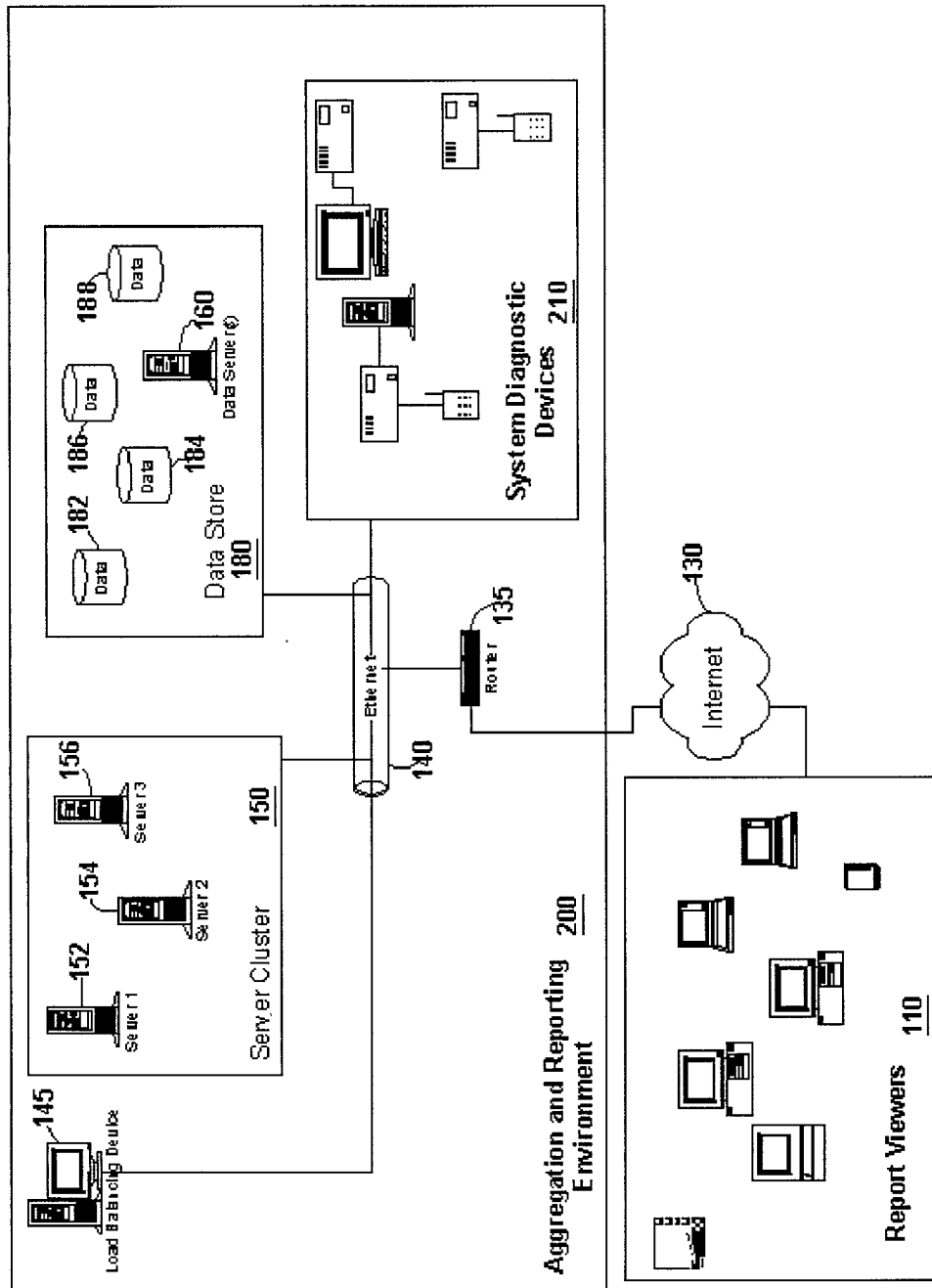


FIG. 3

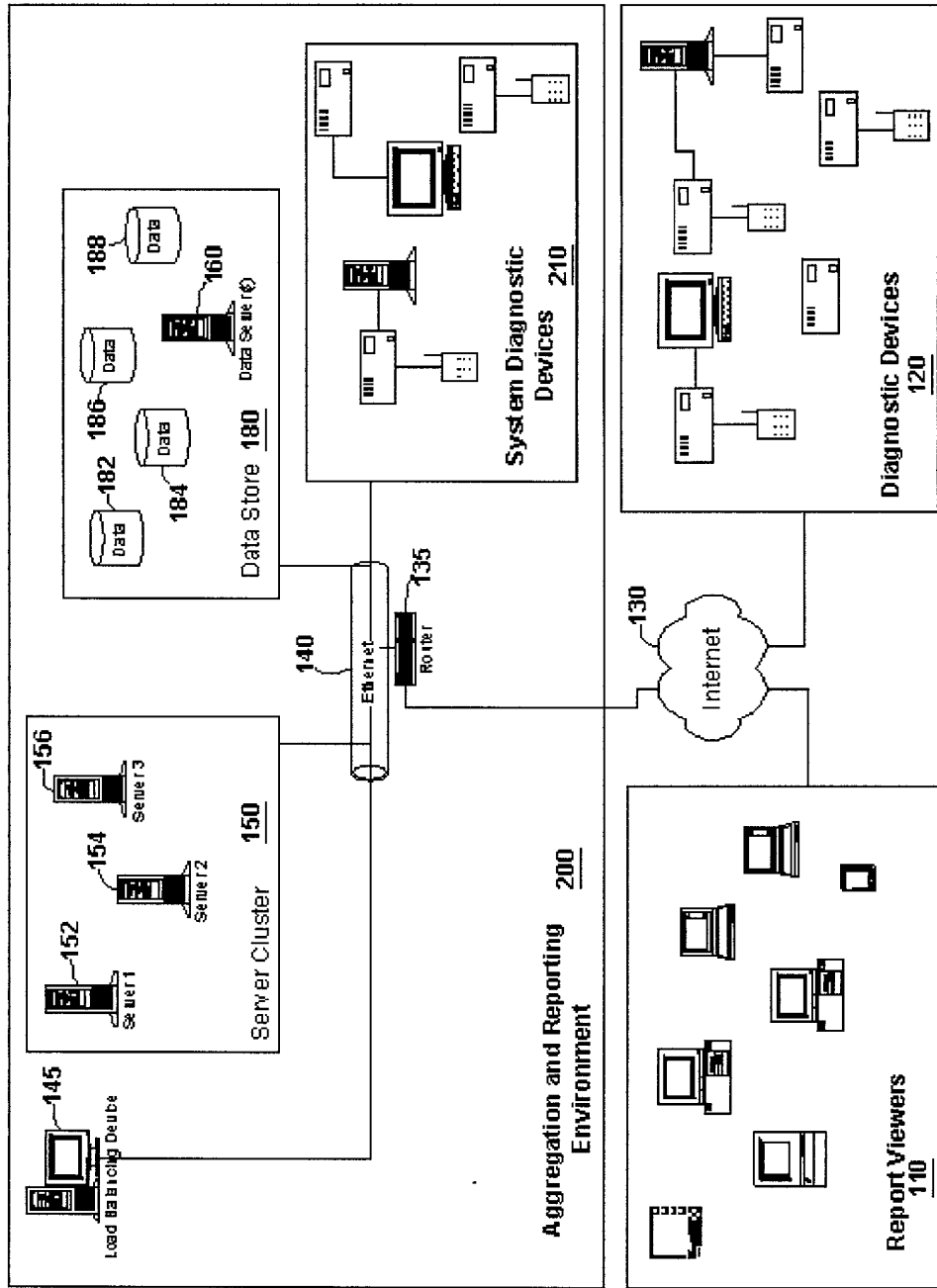


FIG. 4

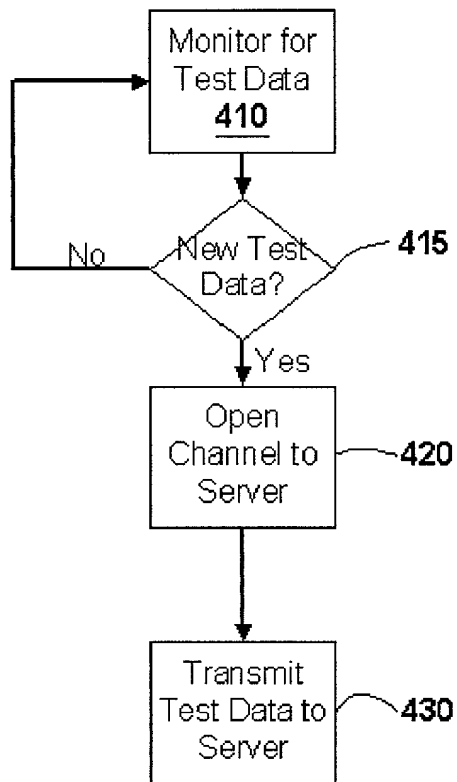


FIG. 5

Analyzer Usage

Date Range: Jan 1, 2001 - Jan 7, 2001

<u>Location</u>	<u>Serial #</u>	<u># Tests Run</u>
ATG	134	12
	234	17
	345	23
	456	90
BHM	98	77
	67	79
	4567	87
	45	92
CAE	1234	101
GSP	2342	77
	23454	92
	3453	99

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FIG. 6

Failure by Model		Date Range: Jan 1, 2001 - Jan 7, 2001		
Manufacturer	Model	Test Name	# Failures	# Times Test Run
Motorola	6120	SAT freq	22	26
		Up speed	16	26
		ST deviation	12	26
	6150	Up speed	22	26
		SAT freq	16	26
		ST deviation	12	26
Nokia	2112	Up speed	44	65
		SAT freq	23	65
		Bad Air	7	65

FIG. 2

Failures by Analyzer	Date Range:	Jan 1, 2001 - Jan 7, 2001
Test Name	Serial #	# Failures # Times Test Run
SAT freq	1234	22 26
	45234	16 26
	2452454	12 26
Up Speed	234545	22 26
	24543	16 26
	2452454	12 26

FIG. 8

Aggregate Failures		Date Range: Jan 1, 2001 - Jan 7, 2001	
Manufacturer	Test Name	# Failures	# Times Test Run
Motorola	SAT freq	22	26
	Up speed	16	26
	ST deviation	12	26
Nokia	Up speed	22	26
	SAT freq	16	26
	ST deviation	12	26